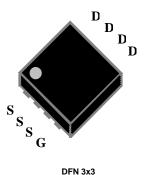


RoHS

COMPLIANT

## 8005H-VB QFN8(3X3) Datasheet N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY					
V <sub>DS</sub> (V)	R <sub>DS(on)</sub> (Ω)	I <sub>D</sub> (A) <sup>a</sup>	Q <sub>g</sub> (Typ.)		
30	0.008 at V <sub>GS</sub> = 10 V	13	6.1 nC		
	0.011 at V <sub>GS</sub> = 4.5 V	11	0.1110		



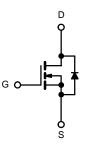
#### FEATURES

- Halogen-free
- Trench Power MOSFET
- Optimized for High-Side Synchronous Rectifier Operation
- 100 % R<sub>g</sub> Tested
- 100 % UIS Tested

#### **APPLICATIONS**

Notebook CPU Core

 High-Side Switch



N-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATINGS</b> $T_A = 25 \text{ °C}$ , unles Parameter		Symbol	Limit	Unit	
Drain-Source Voltage	V <sub>DS</sub>	30	V		
Gate-Source Voltage		V <sub>GS</sub>			± 20
Continuous Drain Current (T <sub>J</sub> = 150 °C) Pulsed Drain Current	$T_{C} = 25 °C$ $T_{C} = 70 °C$ $T_{A} = 25 °C$ $T_{A} = 70 °C$	I <sub>D</sub>	13 10 9 <sup>b, c</sup> 7 <sup>b, c</sup>	A	
Pulsed Drain Current	T <sub>C</sub> = 25 °C	IDM	45		
Continuous Source-Drain Diode Current	$T_{\rm C} = 25  \text{C}$ $T_{\rm A} = 25  \text{°C}$	I <sub>S</sub>	3.7 2.0 <sup>b, c</sup>	-	
Single Pulse Avalanche Current	L _ 0.1 mH	I <sub>AS</sub>	20		
Avalanche Energy L = 0.1 mH		E <sub>AS</sub>	21	mJ	
Maximum Power Dissipation	$T_{C} = 25 °C$ $T_{C} = 70 °C$ $T_{A} = 25 °C$ $T_{A} = 70 °C$	P <sub>D</sub>	4.1 2.5 <u>2.2<sup>b, c</sup></u> 1.3 <sup>b, c</sup>	W	
Operating Junction and Storage Temperature Ra	T <sub>J</sub> , T <sub>stq</sub>	- 55 to 150	°C		

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient <sup>b, d</sup>	t ≤ 10 s	R <sub>thJA</sub>	39	55	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	R <sub>thJF</sub>	25	29		

Notes:

a. Base on T<sub>C</sub> = 25 °C.

b. Surface Mounted on 1" x 1" FR4 board.

c. t = 10 s. d. Maximum under Steady State conditions is 85 °C/W.



SPECIFICATIONS T <sub>J</sub> = 25 °C, unless otherwise noted         Parameter       Symbol         Test Conditions       Min.         Typ.       Max.							
Static	Symbol	Test conditions	WIIII.	Тур.	Wax.	Unit	
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA	30			V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$			26		V	
V <sub>GS(th)</sub> Temperature Coefficient		I <sub>D</sub> = 250 μA		- 6		mV/°C	
( )	$\Delta V_{GS(th)}/T_J$	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250 μA	0.8	- 0	0.5	V	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>				2.5	-	
Gate-Source Leakage	IGSS	$I_{GSS}$ $V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA – μA	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$ $V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 55 \text{ °C}$	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$ = 30 V, V_{CS} = 0 V, T_1 = 55 °C		1 10		
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 V, V_{GS} = 10 V$	20		10	А	
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 10 A		0.008		Ω	
		$V_{GS} = 4.5 \text{ V}, I_D = 9 \text{ A}$		0.011			
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 10 A		50		S	
Dynamic <sup>b</sup>							
Input Capacitance	C <sub>iss</sub>			800		pF	
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 0 V, f = 1 MHz		165			
Reverse Transfer Capacitance	C <sub>rss</sub>			73			
		V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 10 V, I <sub>D</sub> = 10 A		15	23		
Total Gate Charge	Qg			6.8	10.2	nC	
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS} = 15 \text{ V}, \text{ V}_{GS} = 5 \text{ V}, \text{ I}_{D} = 10 \text{ A}$		2.5			
Gate-Drain Charge	Q <sub>gd</sub>			2.3			
Gate Resistance	R <sub>g</sub>	f = 1 MHz	0.36	1.8	3.6	Ω	
Turn-On Delay Time	t <sub>d(on)</sub>			16	23	-	
Rise Time	t <sub>r</sub>	$V_{DD}$ = 15 V, $R_L$ = 1.4 $\Omega$		12	16		
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_{D} \cong$ 9 A, $V_{GEN}$ = 4.5 V, $R_{g}$ = 1 $\Omega$		16	22		
Fall Time	t <sub>f</sub>			10	18		
Turn-On Delay Time	t <sub>d(on)</sub>			8	16	ns	
Rise Time	t <sub>r</sub>	$V_{DD}$ = 15 V, $R_L$ = 1.4 $\Omega$		10	20	-	
Turn-Off Delay Time	t <sub>d(off)</sub>	$\text{I}_\text{D} \cong$ 9 A, $\text{V}_\text{GEN}$ = 10 V, $\text{R}_\text{g}$ = 1 $\Omega$		16	22		
Fall Time	t <sub>f</sub>			8	15		
Drain-Source Body Diode Characterist	tics						
Continuous Source-Drain Diode Current	ا <sub>S</sub>	T <sub>C</sub> = 25 °C			10	A	
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>				50		
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = 9 A		0.8	1.2	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>			15	30	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	-		6	12	nC	
Reverse Recovery Fall Time	t <sub>a</sub>	I <sub>F</sub> = 9 A, dl/dt = 100 A/µs, T <sub>J</sub> = 25 °C		8			
Reverse Recovery Rise Time	t <sub>b</sub>			7		ns	

Notes:

a. Pulse test; pulse width  $\leq$  300  $\mu s,$  duty cycle  $\leq$  2 %.

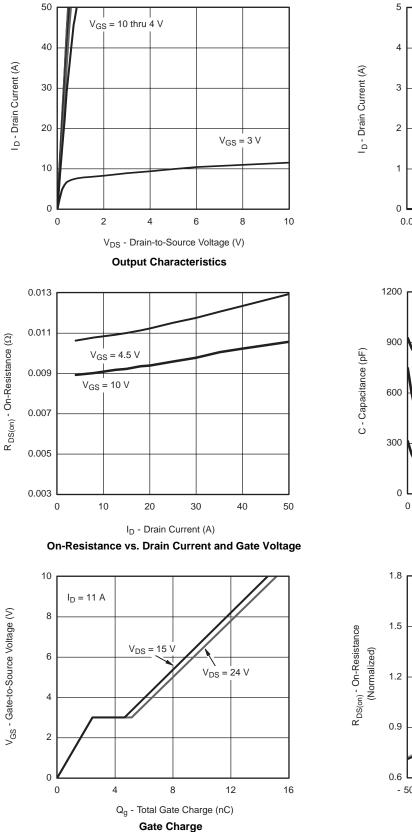
b. Guaranteed by design, not subject to production testing.

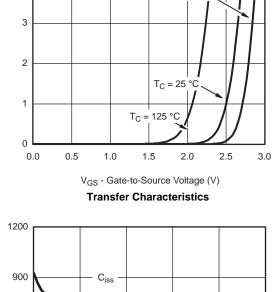
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

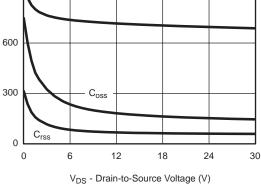


 $T_{\rm C} = -55$ 

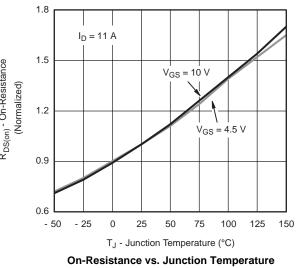
#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted





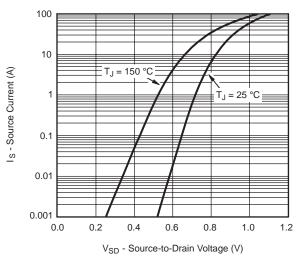


Capacitance

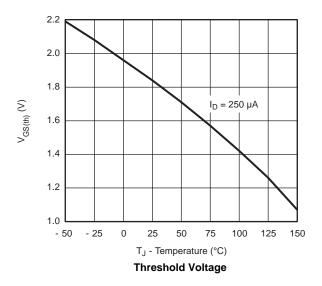


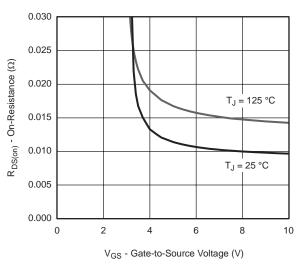


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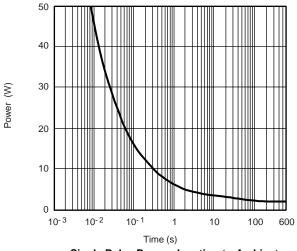




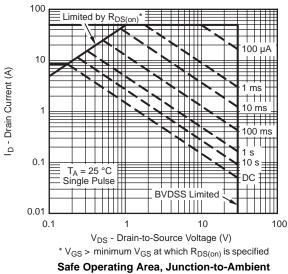




On-Resistance vs. Gate-to-Source Voltage

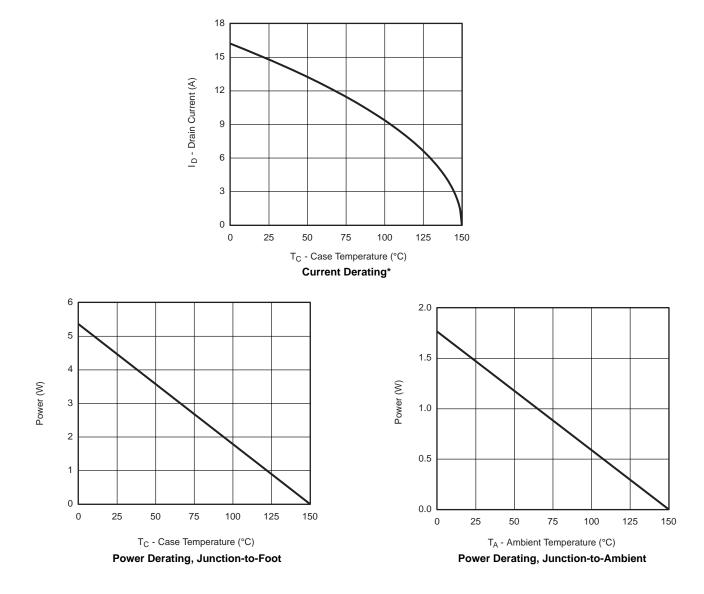








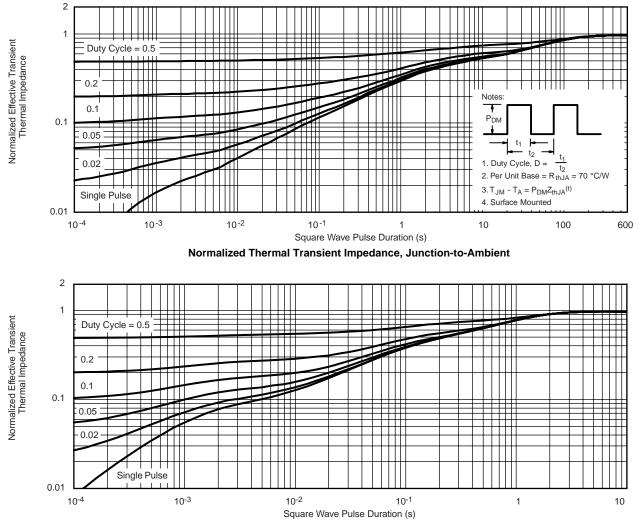
### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



\* The power dissipation  $P_D$  is based on  $T_{J(max)} = 150$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Normalized Thermal Transient Impedance, Junction-to-Foot



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